	Application/Control No.	Applicant(s)/Patent Under Reexamination
Issue Classification	10684445	BAIK, KWANG JUN
	Examiner	Art Unit
	Lamb, Christopher R	2627

Ō	ORIGINAL	INTERNATIONAL	INTERNATIONAL CLASSIFICATION	
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	
369	53.21	G 1 1 B 7/00		
CROSS R	CROSS REFERENCE(S)			
CLASS SUBCLAS	SUBCLASS (ONE SUBCLASS PER BLOCK)			
Christopher Lamb 11/21/06	CRL	Bon Korxuel	Total Claims Allowed:	
(Assistant Examiner) (Date)	SUPER	WILLIAM KORŻÓCH SUPERVISORY PATENT EXAMINER	16	
F		NOLOGY CENTER 2600	O.G. Print Claim(s) O.G. Print Figure	Figure
(Legal Instruments Examiner) (Date)	(Primary Examiner)	(Date)		,

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